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TITLE: **MEMORY TESTING** DEVICE

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ABSTRACT:

   PURPOSE: To shorten the testing time by providing a memory
selector which
simultaneously accesses plural bank memories, automatically selecting
the
output of the memory, and comparing it with test data.

   CONSTITUTION: In a **memory test** mode, a memory selector 7 outputs
chip
selecting signals to bank memories 2 to 5, simultaneously reads the
data, and a
selector control 12 applys a memory output selective signal to a data
selector
13. Next, the **selector** 13 applys the **selected memory output data** to
a data
comparator 15, and the comparator 15 compares the data with the test
data set
in a data register 14 beforehand. Thus a testing operation can be
completed in
the ready cycle of the memory 2 by a processor 16.